

Data sheet acquired from Harris Semiconductor SCHS082C - Revised October 2003

### **CMOS 8-Bit Priority Encoder**

High-Voltage Types (20-Volt Rating)

■ CD4532B consists of combinational logic that encodes the highest priority input (D7-D0) to a 3-bit binary code. The eight inputs, D7 through D0, each have an assigned priority; D7 is the highest priority and D0 is the lowest. The priority encoder is inhibited when the chip-enable input Ei is low. When E<sub>1</sub> is high, the binary representation of the highest-priority input appears on output lines Q2-Q0, and the group select line GS is high to indicate that priority inputs are present. The enable-out (E<sub>O</sub>) is high when no priority inputs are present. If any one input is high, EO is low and all cascaded lower-order stages are disabled.

The CD4532B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

#### Features:

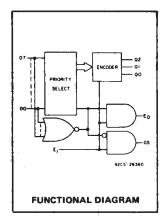
- Converts from 1 of 8 to binary
- Provides cascading feature to handle any number of inputs
- Group select indicates one or more priority inputs
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V over full package temperature range; 100 nA at 18 V and 25°C
- Noise margin (full-package-temperature range):

0.5 V at V<sub>DD</sub> = 5 V 1.5 V at V<sub>DD</sub> = 10 V 1.5 V at V<sub>DD</sub> = 15 V

- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

#### Applications:

- Priority encoder
- Binary or BCD encoder (keyboard encoding)
- Floating point arithmetic



CD4532B Types

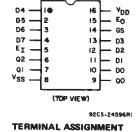
#### **RECOMMENDED OPERATING CONDITIONS**

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges.

Characteristic	Min.	Max	Units
Supply Voltage Range (for T <sub>A</sub> =	3	18	V
Full Package Temp. Range)			

#### MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (VDD) INPUT VOLTAGE RANGE, ALL INPUTS .....-0.5V to VDD +0.5V POWER DISSIPATION PER PACKAGE (PD): For T<sub>A</sub> = +100°C to +125°C ...... Derate Linearity at 12mW/°C to 200mW DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)........... 100mW OPERATING-TEMPERATURE RANGE (TA) .....-55°C to +125°C STORAGE TEMPERATURE RANGE (Tstg) .....-65°C to +150°C LEAD TEMPERATURE (DURING SOLDERING): 



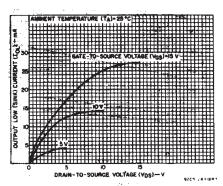


Fig. 1 — Typical output low (sink) current

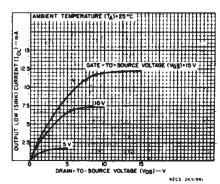


Fig. 2 - Minimum output low (sink) current characteristics.

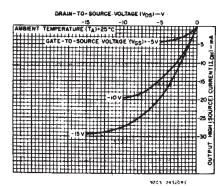


Fig. 3 — Typical output high (source) current characteristics.

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#### STATIC ELECTRICAL CHARACTERISTICS

CHARACTER-	CONE	IS	LIMITS AT INDICATED TEMPERATURES (°C)							UNITS		
ISTIC	vo	VIN	VDD						+25		0	
	(V)	(V)	(V)	-55	<del>-4</del> 0	+85	+125	Min.	Тур.	Max.		
Quiescent Device		0,5	5	5	5	150	150	-	0.04	5		
Current,	_	0,10	10	10	10	300	300	-	0.04	10		
IDD Max.	_	0,15	15	20	20	600	600	-	0.04	20	μΑ	
		0,20	20	100	100	3000	3000	_	0.08	100		
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-		
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6			
IOL Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	_		
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	mA	
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	- <del>-</del>		
Current, IOH Min.	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	- <del>-</del>		
TOH WATER	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8			
Output Voltage:	_	0,5	5		0	.05		_	0	0.05		
Low-Level, VOL Max.	-	0,10	10		0	.05			0	0.05		
VUL Max.	-	0,15	15		0	.05		-	0	0.05	l v	
Output Voltage:		0,5	5		4	.95		4.95	5	-	ľ	
High-Level,	. –	0,10	10		9	95		9.95	10			
VOH Min.	_	0,15	15		14	1.95		14.95	15			
Input Low	0.5, 4.5	1	5			1		-		1.5		
Voltage, V <sub>IL</sub> Max.*	1, 9	-	10		2	.5		-	_	3		
VIL Max.	1.5,13.5	_	15			3		_		4	v	
Input High	0.5, 4.5	_	5			4		3.5	_	_	<b>,</b>	
Voltage,	1, 9		10		7	.5		7				
VIH Min.	1.5,13.5	_	15		1	2		11	_	_		
Input Current IIN Max.		0,18	18	±0.1	±0.1	±1	±1	_	±10 <sup>-5</sup>	±0.1	μА	

<sup>\*</sup>One input is tested at a time; other inputs should be at  $V_{DD}$  or  $V_{SS}$ . For testing all inputs at  $V_{IL}$  and  $V_{IH}$  levels, use 20%/80%  $V_{DD}$ .

# DYNAMIC ELECTRICAL CHARACTERISTICS at T\_A=25°C; C\_L=50 pF, Input t\_r,t\_f= 20 ns, R\_L=200 K $\Omega$

CHARACTERISTIC	TEST CONDITIONS VDD	LIF	UNITS		
	VOLTS	TYP.	TYP. MAX.		
Propagation Delay Time tpHL, tpLH	5	110	220		
E <sub>I</sub> to E <sub>O</sub> , E <sub>I</sub> to GS	10	55	110		
	15	45	85	1	
	5	170	340	1	
Et to Qm, Dn to GS	10	85	170	ns	
	15	65	125	1	
	5	220	440		
Dn to Q <sub>M</sub>	10	110	220		
	15	85	160	[	
	5	100	200		
Transition Time tTHL, tTLH	10	50	100	ns	
<u> </u>	15	40	80		
Input Capacitance CIN	Any Input	5	7.5	pF	

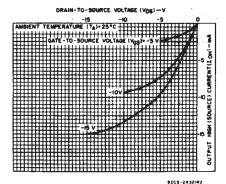


Fig. 4 — Minimum output high (source) current characteristics.

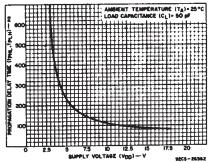


Fig. 5 — Typical propagation delay (Dn to Qm) vs. supply voltage.

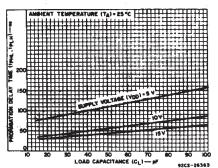


Fig. 6 — Typical propagation delay (E<sub>1</sub> to GS, E<sub>1</sub> to E<sub>O</sub>) vs. load capacitance.

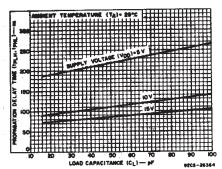


Fig. 7 — Typical propagation delay (Dn to Qm) vs. load capacitance.

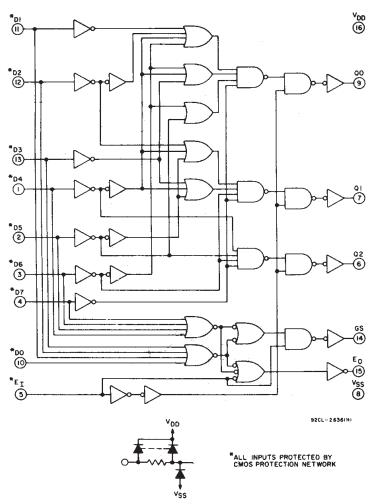


Fig. 8 — CD4532 logic diagram.

#### TRUTH TABLE

			,			Dutput							
Εį	D7	D6	D5	D4	D3	D2	D1	D0	GS	Q2	Q1	Q0	Eo
0	Х	Х	Х	Х	Х	X.	Х	X	Ō	0	0	0	0
1	0	0	0	0	0	0	0	0	0	0	0	0	1
1	1	Χ.	х	Х	Х	Х	×	Х	1	1	1	1	0
1	0	1	Х	х	x	Х	×	Х	1	1.	1	0	0
1	0	0	1	Х	×	Х	×	х	1	1	0	1	0
1	0	0	0	1	×	Х	x	Х	1	1	0	0	0
1	0	0	0	0	1	Х	Х	Х	1	0	1	1	0
1	0	0	0	0	0	1	×	х	1	0	1	0	0
1	0	0	0	0	0	0	1	х	1	0	0	1	0
1	0	0	0	0	0	0	0	1	1	0	0	0	0

X = Don't Care Logic 1  $\equiv$  High Logic 0  $\equiv$  Low

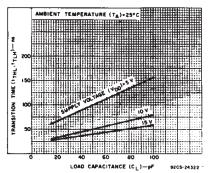


Fig.9 – Typical transition time vs. load capacitance.

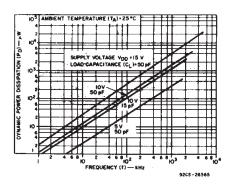


Fig. 10 — Typical dynamic power dissipation vs. fraquency.

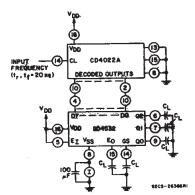


Fig.11 — Dynamic power dissipation test circuit.

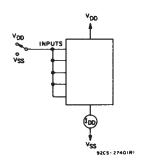


Fig. 12 - Quiescent device current test circuit.

### CD4532B Types

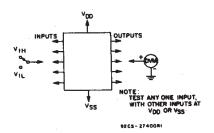


Fig. 13 - Input voltage test circuit.

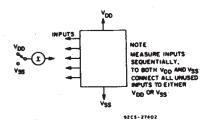
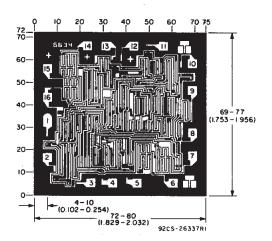


Fig. 14 - Input current test circuit.



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils  $(10^{-3})$  inch).

Dimensions and pad layout for CD4532BH.

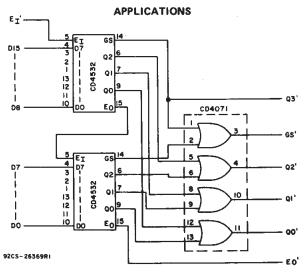
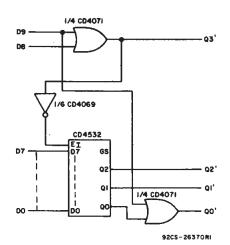


Fig. 15 - 16-level priority encoder.



TRUTH TABLE

ſ					Output												
ſ	D9	D8	D7	D6	<b>D</b> 5	D4	D3	D2	D1	DO	GS	σ3.	Q2'	01'	GO,		
ſ	1	х	х	х	х	Х	х	х	Х	х	0	1	0	0	1		
ı	0	1	x	X	Х	×	X	Х	Х	X	0	1	0	0	0		
ľ	0	0	1	х	Х	Х	Х	Х	X	X	1-	0	1	1	1		
1	0	0	0	1 -	x	х	X	X.	X	х	1	0	1	1	0		
1	0	0	0	0	1	X	X	X	Х	Х	1	0	1	0	1		
ı	0	0	0	0	0	_1_	X	X	Х	Х	1 1	0	1	0	0		
I	0	0	0	0	0	0	1	Х	Х	Х	1	0.	0	1	1		
ł	0	0	0	0	0	0	0	1	Х	х	1	- 0	0	1	0		
١	0	0	0	0	0	0	0	0	1	х	1	0	0	0	1		
ı	0	0	0	0	0	0	0	0	0	1	1	0	0	0	0		
	X = Don't Care							Logic 1 ≡ High						Logic 0 ≡ Low			

Fig.16 - 0-to-9 keyboard encoder.





i.com 28-Feb-2005

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
CD4532BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	Level-NC-NC-NC
CD4532BF3A	ACTIVE	CDIP	J	16	1	None	Call TI	Level-NC-NC-NC
CD4532BM	ACTIVE	SOIC	D	16	40	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4532BM96	ACTIVE	SOIC	D	16	2500	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4532BMT	ACTIVE	SOIC	D	16	250	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4532BNSR	ACTIVE	SO	NS	16	2000	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4532BPW	ACTIVE	TSSOP	PW	16	90	Pb-Free (RoHS)	CU NIPDAU	Level-1-250C-UNLIM
CD4532BPWR	ACTIVE	TSSOP	PW	16	2000	Pb-Free (RoHS)	CU NIPDAU	Level-1-250C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

None: Not yet available Lead (Pb-Free).

**Pb-Free** (RoHS): Ti's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

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#### 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

### N (R-PDIP-T\*\*)

### PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN

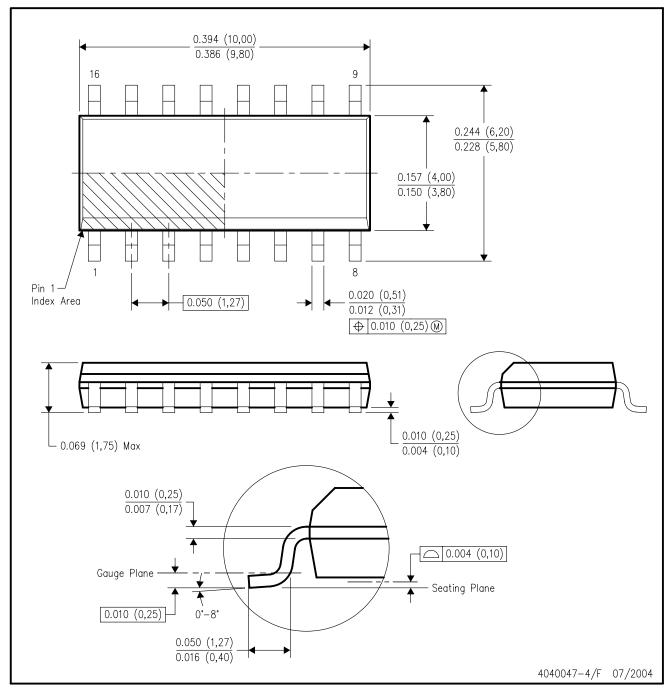


- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



# D (R-PDSO-G16)

### PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012 variation AC.



### **MECHANICAL DATA**

### NS (R-PDSO-G\*\*)

## 14-PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



### PW (R-PDSO-G\*\*)

#### 14 PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153